Proposal for a spintronic fem to-Tesla magnetic eld sensor

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A bstract

We propose a spintronic magnetic eld sensor, fashioned out of quantum wires, which may be capable of detecting very weak magnetic elds with a sensitivity of 1 fr / Hz at a temperature of 42 K, and 80 fr / Hz at room temperature. Such sensors have commercial applications in magnetometry, quantum computing, solid state nuclear magnetic resonance, magneto-encephalography, and military applications in weapon detection.

Keywords: spintronics, magnetic sensors, spin orbit interaction PACS: 85.75 Hh, 72.25 D c, 71.70 E j There is considerable interest in devising magnetic eld sensors capable of detecting weak dc and ac magnetic elds. In this paper, we describe a novel concept for realizing such a device utilizing spin orbit coupling e ects in a quantum wire.

Consider a sem iconductor quantum wire with weak (or non-existent) D resselhaus spin orbit interaction [1], but a strong R ashba spin orbit interaction [2] caused by an external transverse electric eld. The D resselhaus interaction accrues from bulk inversion asym m etry and is therefore virtually non-existent in centro-sym m etric crystals, whereas the R ashba interaction arises from structural inversion asym m etry and hence can be m ade large by applying a high sym m etry breaking transverse electric eld. W e will assume that the wire is along the x-direction and the external electric eld inducing the R ashba e ect is along the y-direction (see Fig. 1).

This device is now brought into contact with the external magnetic eld to be detected, and oriented such that the eld is directed along the wire axis (i.e. x-axis). A sum ing that the eld has a magnetic ux density B, the e ective mass H am iltonian for the wire, in the Landau gauge A = (0, Bz, 0), can be written as

$$H = (p_x^2 + p_y^2 + p_z^2) = (2m) + (eB z p_y) = m + (e^2 B^2 z^2) = (2m) \quad (g=2)_B B_x + V_y (y) + V_z (z) + [(p_x=-)_z (p_z=-)_x]$$
(1)

where g is the Lande g-factor, $_{\rm B}$ is the Bohr m agneton, $V_{\rm y}(y)$ and $V_{\rm z}(z)$ are the con ning potentials along the y- and z-directions, -s are the Pauli spin matrices, and is the strength of the Rashba spin-orbit interaction in the wire.

W e will assume that the wire is narrow enough and the temperature is low enough that only the lowest magneto-electric subband is occupied. In that case, the Ham iltonian simpli es to [3]

$$H = \sim^{2} k_{x}^{2} = (2m) + E_{0} \qquad x + k_{x z}$$
(2)

where E_0 is the energy of the lowest magneto-electric subband and = $g_B B = 2$.

D isognalizing this Ham iltonian in a truncated Hilbert space spanning the two spin resolved states in the lowest subband yields the eigenenergies

$$E = \frac{-2k_{x}^{2}}{2m} + E_{0} \qquad (3)$$

and the corresponding eigenstates



Fig. 1. Physical structure of the magnetic eld sensor.

 ${}_{+}(B;x) = \begin{cases} 2 & 3 \\ 6 & \cos(x_{x}) & \frac{2}{5} & e^{ik_{x}x} \\ \sin(x_{x}) & \sin(x_{x}) \end{cases} (B;x) = \begin{cases} 2 & 3 \\ \sin(x_{x}) & \frac{2}{5} & e^{ik_{x}x} \\ \cos(x_{x}) & \cos(x_{x}) \end{cases} (4)$

where $k_x = -(1=2)\arctan[= k_x]$.

Note that if the magnetic ux density B = 0, so that = 0, then the energy dispersion relations given in Equation (3) are parabolic, but more importantly, the eigenspinors given in Equation (4) are independent of k_x because k_x becomes independent of k_x . In fact, the eigenspinors become [1, 0] and [0, 1], which are + z-polarized and -z-polarized states. Therefore, with B = 0, each of the spin resolved subbands will have a densite spin quantization axis (+ z-polarized and -z-polarized). Furtherm ore, these quantization axes are anti-parallel since the eigenspinors are orthogonal. As a result, there are no two states in the two spin-resolved subbands that can be coupled by any non-m agnetic scatterer, be it an in purity or a phonon, or anything else. Hence, if a carrier is injected into the wire with its spin either + z-polarized or -z-polarized, then the spin will not relax (or ip) no matter how frequently energy and momentum relaxing scattering events take place. The Elliott-Y afet mechanism of spin relaxation [4] will also be completely suppressed since the eigenspinors are momentum independent. Furtherm ore, there is no D'yakonov-Perel' spin

relaxation in a quantum wire if only a single subband is occupied [5]. Therefore, spin transport will be ballistic when B = 0, even if charge transport is not. In other words, the spin relaxation length would have been in nite were it not for such e ects as hyper ne interaction with nuclear spins which can relax electron spin. Such relaxation can be made virtually non-existent by appropriate choice of (isotopically pure) materials. Even in materials that have isotopes with strong nuclear spin, the spin relaxation rate due to hyper ne interaction is very small.

Now consider the situation when the magnetic eld is non-zero (\leq 0). Then the eigenspinors given by Equation (4) are wavevector dependent. In this case, neither subband has a de nite spin quantization axis since the spin state in either subband depends on the wavevector. Consequently, it is always possible to nd two states in the two subbands with non-orthogonal spins. Any nonmagnetic scatterer (impurity, phonon, etc.) can then couple these two states and cause a spin-relaxing scattering event. In this case, no matter what spin eigenstate the carrier is injected in, spin transport is non-ballistic. That is to say, the spin relaxation length is much shorter compared to the case when there is no magnetic eld. Since phonon scattering can ip spin in the presence of a magnetic eld, and phonon scattering is quite strong in quantum wires (because of the van Hove singularity in the density of states) [6], the spin relaxation length can be rather small in the presence of a magnetic eld. Therefore, a magnetic eld drastically reduces the spin relaxation length. This is the basis of the magnetic eld sensor.

The way the sensor works is as follows. Using a ferrom agnetic spin in jector contact magnetized in the + z-direction, we will in ject carriers into the wire with + z-polarized spins. The ferrom agnetic contact results in a magnetic eld directed mostly in the z-direction, but also with some small fringing com ponent along the x-direction. The z-directed component of the eld does not matter, since it does not extend along the wire, which is in the x-direction. However, any x-directed component will matter. Fortunately, the fringing eld decays very quickly and if the wire is long enough, we can neglect the e ect of the fringing eld. Therefore, in the absence of any external x-directed m agnetic eld, an injected electron will arrive with its spin polarization practically intact at the other end where another ferrom agnetic contact (m agnetized in the + z-direction) is placed. This second contact will then transmit the carrier completely and the spin polarized current will be high so that the device resistance will be bw. How ever, if there is an external x-directed magnetic eld, then the injected spin is no longer an eigenstate and therefore can ip in the channel [8] and arrive at the second contact with arbitrary polarization. In fact, if the wire is long enough (much longer than the spin relaxation length), then the spin polarization of the current arriving at the second contact would have essentially decayed to zero, so that there is equal probability of an electron being transmitted or relected. In this case, the device conductance can

decrease by 50% compared to the case when there is no magnetic eld. This of course assumes that every carrier was initially injected with its spin completely polarized in the +z-direction. In other words, the spin injection e ciency is 100%. A more realistic scenario is to assume, say, a 32% injection e ciency since it has already been demonstrated in an Fe/G aA s heterostructure [9]. For 32% injection e ciency, the conductance will decrease by 24% in a magnetic eld. W e will err on the side of caution and assume conservatively that the device conductance will decrease by only 10% in a magnetic eld. A recent self-consistent drift di usion simulation, carried out for a similar type of device, has shown that the conductance decreases by 20 - 30% because of spin ip scatterings [10].

At this point, we mention that the idea of changing device resistance by modulating spin ip scattering was the basis of a recently proposed \spin eld e ect transistor" [11]. Unfortunately, the sm all conductance modulation achievable by this technique (maximum 50%) is insu cient for a \transistor" which is an active device requiring a conductance modulation by three orders of magnitude to be useful. In contrast, the device proposed here is a passive sensor that does not have the stringent requirem ents of a transistor and, as we show below, a 10% conductance modulation is adequate to provide excellent sensitivity.

Let us now estim ate how much magnetic eld can decrease the device conductance by the assumed 10%. Roughly speaking, this could correspond to the situation

$$\frac{1}{k_{\rm F}}$$
 0.1 (5)

where k_F is the Ferm i wavevector in the channel. For a linear carrier concentration of 5 10^4 /cm, k_F 8 10^6 /m. The measured value of in materials such as InAs is of the order of 10^{11} eV-m [7]. Form ost materials (with weaker Rashba e ect), the value of may be two orders of magnitude smaller. Actually, this value can be tuned with an external electric eld. Therefore, it is reasonable to estimate that k_F 1 eV. The magnetic eld that can cause the 10% decrease in the conductance of the device is then found from Equation (5) to be 100e, if we assume jgj 15.

We now carry out a standard sensitivity analysis following ref. [12]. The rm s noise current for a single wire is taken to be the Johnson noise current given by $I_n = \frac{P}{4kTG} = C + \frac{F}{G}$, where k is the Boltzm ann constant, T is the absolute temperature, G is the device conductance, f is the noise bandwidth, and C = $\frac{P}{4kT} = \frac{F}{F}$. In reality, the noise current can be suppressed in a quantum wire by two orders of magnitude because of phonon con nem ent [6]. Therefore, $I_n = C + \frac{F}{G}$, where is the noise suppression factor which is about 0.01. There m ay be also other sources of noise, such as 1/fnoise, but this too is suppressed

in quantum wires. 1/fnoise can be reduced by operating the sensor under an ac bias with high frequency.

The change in current through a wire in a magnetic eld H is the signal current I_s and is expressed as SH, where S is the sensitivity. W e will assume that the current drops linearly in a magnetic eld, so that S is independent of H. In reality, the current is more likely to drop superlinearly with magnetic eld so that S will be larger at smaller magnetic eld. This is favorable for detecting small magnetic elds, but since we intend to remain conservative, we will assume that S is independent of magnetic eld. Therefore, the signal to noise ratio for a single wire is

$$(S : N)_1 = \frac{SH}{I_n} = \frac{SH}{C \frac{P}{G}}$$
 (6)

The noise current of N w ires in parallel is $C \stackrel{\text{p}}{\text{NG}}$, whereas the signal current is N SH. Therefore, the signal-to-noise ratio of N w ires in parallel is $\stackrel{\text{N}}{\text{N}}$ times that of a single w ire.

For a carrier concentration of 5 10^4 /cm as we have assumed, and for a mobility of only 25 cm²/V-sec (at 42 K), a single wire of length 10 m has a conductance G 2 10^{10} Siemens. At a 100 mV bias, the current through a single wire is therefore 20 pA. Consequently, a 10% change in conductance produces a change of current by 2 pA. Since the 10% change in conductance is produced at 10 Oe, the sensitivity S = 0.2 pA/Oe. At 1 fT (= 10^{11} Oe), the signal current I_s for a single wire = SH = 2 10^{24} A, whereas the noise current at a temperature of 4.2 K is 2 10^{18} A/ H z. Therefore the signal to noise ratio for a single wire is 10^6 :1/ H z and that for a parallel array of 10^{12} wires is 1.1/ H z. Consequently, the optimum sensitivity is about 1 fT / H z at 4.2 K. If we repeat the calculation for 300 K (assuming that the m obility is reduced by a factor of 100 from its value at 4.2 K), the optimum sensitivity is about 80 fT / H z.

We now calculate the power consumption of the sensor. The power dissipated in a single wire is 20 pA 100 mV = 2 pW and for an array of 10^{12} wires, the total power dissipation is 2 W at 4.2 K. At room temperature, the conductance of each wire is reduced by approximately a factor of 100 because of m obility degradation, so that the power dissipation is reduced to 20 m W for the array. Therefore, the sensor we have designed is a low power sensor.

It should be obvious from the foregoing analysis that we can increase the sensitivity, without concom itantly increasing power dissipation, if we decrease the carrier concentration in the wire, but increase the mobility or decrease the wire length, to keep the conductance the same. This could allow sub-fem to-Tesla eld detection.

At a bias of 100 mV, the average electric eld over a 10 m long wire is 100 V/cm. In the past, M onte Carlo simulation of carrier transport has shown that even at a much higher eld than this, transport remains primarily single channeled in a quantum wire because of the extrem ely e cient acoustic phonon mediated energy relaxation [13]. Therefore, the assumption of single channeled transport is mostly valid.

F inally, one needs to identify a realistic route to fabricating an array of 10^{12} quantum wires. We propose using a porous alum ina template technique for this purpose. The required sequence of steps is shown in Fig. 2. A thin foil of alum inum is electropolished and then anodized in 15% sulfuric acid at 25 V dc and at a temperature of 0 C to produce a porous alum ina lm containing an ordered array of pores with diameter 25 nm [14]. A sem iconductor is then selectively electrodeposited within the pores [15,16] to create an array of vertically standing nanow ires of 25 nm diameter. The density of wires is typically 10^{11} /cm², so that 10^{12} wires require an area of 10 cm². Next a ferrom agnetic m etal is electrodeposited within the pores [17] on top of the sem iconductor. The pores are slightly over lled so that the ferrom agnetic m etal m akes a two-dimensional layer on top. This is then covered with an organic layer to provide m echanical stability during the later steps.

The alum inum foil is then dissolved in $\operatorname{HgC} {}_{2}$, and the alum ina barrier layer at the bottom of the pores is etched in phosphoric acid to open up the pores from the bottom .A nother ferrom agnet is then electrodeposited on the exposed tips of the sem iconductor wires through a mask. The organic layer is then dissolved in acetone and the multilayered lm is harvested and placed on top of a conducting substrate covered with silver paste. Two wires are attached to two remote di used Schottky contacts in order to apply a transverse electric eld that induces the Rashba e ect. Finally wires are attached to top and bottom to provide ohm ic electrical contacts. This com pletes the fabrication of the sensor.

In conclusion, we have proposed a highly sensitive solid-state m agnetic eld detector based on spin orbit interaction. Such sensors can operate at room temperature since the energy separation between subbands can exceed the room temperature therm all energy in 25-nm diameter wires. The sensitivity of these sensors could be comparable to those of superconducting quantum interference devices [18{20}] and therefore m ay be appropriate for m agnetoencephalography where one directly senses the very sm allm agnetic elds produced by neural activity in hum an brains.

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Fig. 2. Fabrication steps. (a) C reation of a porous alum ina $\ln w$ ith 25 nm diam eter pores. This is produced by anodizing an alum inum foil at 25 V dc in sulfuric acid at 0 C. (b) E lectrodepositing a sem iconductor selectively within the pores. (c) E lectrodepositing a ferrom agnetic layer on top. This could be either a m etallic ferrom agnet, or a sem iconducting ferrom agnet such as ZnM nSe. (d) Pasting a thick organic layer on top form echanical stability of the structure. (e) D issolving out the A l foil in HgC l₂. (f) E tching the alum ina in phosphoric acid at room temperature to expose the tips of the sem iconductor w ires. (g) E vaporating a ferrom agnet on the tips of the sem iconductor w ires through a m ask. (h) D issolving the organic layer in ethanol, harvesting the lm and placing it on top of a conducting substrate covered with silver paste. (i) M aking Schottky contacts on the sides and ohm ic contacts at top and bottom.

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